Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/632,233	OLKER ET AL.	
Examiner	Art Unit	
DIANE D. MIZRAHI	2165	

SEARCHED				
Class	Subclass	Date	Examiner	
707	1-10; 100- 104.1, 200-206	1/21/2006	DM	
709	201,203,			
	207,214			
	219,227,			
	236,228			
719	330			
715	765,764			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INVENTOR SEARCH; 101/QAS PANEL; DOUBLE PATENTING; USPTO;	1/21/2006	DM		
USPG; EPO; JPO; DERWENT; IBM TECH; DERWENT; INTERNET; NPL; PERSONAL DIGESTS				
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